

In the Claims:

Claim 1 (amended). An integrated circuit component,
comprising:

B2 a plurality of circuit points being not externally accessible,
providing various electrical^{15, 16, 17 or 14, 14, 20} signals of the integrated circuit
component to be measured or analyzed;

at least one connecting contact point^{2 or 3} externally accessible; *for what?*
and

a multiplexer having an output connected to said at least one
connecting contact point and having a plurality of inputs,
each one of said plurality of inputs being connected to a
respective one of said plurality of circuit points.

B3 Claim 2 (amended). The integrated circuit^{component} according to claim
1, wherein:

said at least one connecting contact point is one of a
plurality^{2, 3} of connecting contact points;

Spec do not show a reference signal is selectively applied to one of said
plurality of connecting contact points and passed on via a
route within the integrated circuit component to one of said
plurality of circuit points that are not externally
accessible; and *with what not show in 207*

ref. signal
at
elec. signal
LAB
said signals to be measured or analyzed can be selectively
passed on via routes within the integrated circuit component
from said plurality of circuit points that are not externally
accessible to said plurality of connecting contact points
other than said one of said plurality of connecting contact
points.

Claim 3 (amended). The integrated circuit according to claim
2, wherein said plurality of connecting contact points is
exactly two connecting contact points.

Claim 4 (amended). The integrated circuit according to claim
1, wherein:

said electrical signals are internal chip signals in the
integrated circuit component; and

112
what supply
the signal
a reference signals and said electrical signals can be
selectively passed on to said at least one connecting contact
point.

it was withdrawn
condition
PO
1
help
to
Examin
with ACE
Claim 5 (amended). The integrated circuit according to claim
1, comprising a package and wherein:

using
want
112
component
said plurality of connecting contact points define a plurality
of inaccessible contact points disposed on said package;

128
said electrical signals at said plurality of circuit points
that are not externally accessible are present at said
plurality of inaccessible contact points;

129
said electrical signals and reference signals are selectively
passed on to said at least one connecting contact point; and

130
said at least one connecting contact point is formed by at
least one of said plurality of inaccessible contact points.

131
Claim 6 (amended). The integrated circuit according to claim
5, wherein:

132
said package is a ball grid array package having a lower face;

133
said plurality of inaccessible contact points are located on
said lower face of said package and are thus concealed between
said package and a system board on which said package is
fitted; and

134
said at least one connecting contact point is electrically
conductively connected to a corresponding number of metallic
test points on the system board.

135
Claim 7 (amended). The integrated circuit according to claim
[1] 3, [wherein a time-controlled] further comprising a second
multiplexing circuit [is provided for selectively passing on

the electrical signals to said at least one external test connecting contact point].

Claim 8 (amended). The integrated circuit ^{component} according to claim 1, wherein:

33 cont. said multiplexing circuit is time-controlled and is provided in the integrated circuit component surrounded by a ball grid array package. 112 3

Claim 9 (amended). The integrated circuit ^{component} according to claim 7, wherein said multiplexing circuit is programmably controlled to predetermine selective passing on of the electrical signals to said at least one connecting contact point. 112 who does this

Claim 10 (amended). The integrated circuit ^{component} according to claim 1, wherein said at least one connecting contact point can be selectively used in an opposite operating direction for inputting signals to said plurality of circuit points that are not externally accessible. 112

Claim 11 (amended). The integrated circuit ^{component} according to claim 1, wherein said at least one connecting contact point is connected to a component tester for analyzing the electrical signals ^{located where i.e. inside or outside of} at, at least some of said plurality of circuit points. component

Claim 12 (amended). The integrated circuit ^{component} according to claim 1, wherein said at least one connecting contact point is connected to a system and an application of said system analyzes the electrical signals ^{at} ^{of} at least some of said plurality of circuit points.

Claim 13 (amended). The integrated circuit ^{component} according to claim 1, wherein said at least one connecting contact point is used for analyzing a system in which said integrated circuit ^{component} is used.

[Enter The Following New Claims:]

-- 17. An integrated circuit component, comprising:

a first plurality ^{15, 16, 17} of circuit points of the integrated circuit ^{18, 19} not being externally accessible;

a second plurality ^{14, 19, 20} of circuit points of the integrated circuit ^{18, 19} not being externally accessible;

a first connecting contact point ² being externally accessible;

a second connecting contact point ³ being externally accessible;

a first multiplexer ² having an output ²¹ connected to said first connecting contact point and having a plurality of inputs,

^{9, 10, 11}

each one of said plurality of inputs being connected to a respective one of said first plurality of circuit points; and a second ⁴ multiplexer having an output connected to said second connecting contact point and having a plurality ^(2, 3, 4) of inputs, each one of said plurality of inputs being connected to a respective one of said second plurality of circuit points.

B4
concl

18. The integrated circuit component according to claim 17, wherein:

said first connecting contact point receives and passes on a reference signal via a route within the integrated circuit component to one of said first plurality of circuit points that are not externally accessible; and

said second plurality of circuit points of the integrated circuit are providing electrical signals to be measured or analyzed, one of said second plurality of circuit points being connected to said second connecting contact point. --